TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC7WH157FU,TC7WH157FK

## 2-Channel Multiplexer

The TC7WH157 is an advanced high speed CMOS 2-Channel Multiplexer fabricated with silicon gate CMOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation. It consists of 2-input digital multiplexer with common select and strobe inputs.

When the STROBE input is held "H" level, selection of data is inhibited and all the outputs become "L" level.

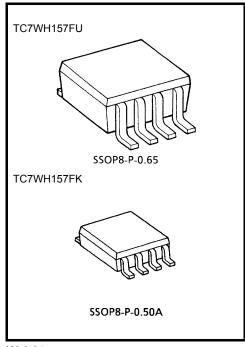
The SELECT decoding determines whether the A or B inputs get routed to their corresponding Y outputs.

An input protection circuit ensures that 0 to 7 V can be applied to the input pins without regard to the supply voltage.

This device can be used to interface 5 V to 3 V systems and two supply systems such as battery back up. This circuit prevents device destruction due to mismatched supply and input voltages.

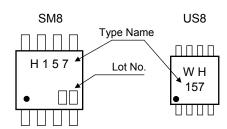
#### **Features**

- High speed:  $t_{pd} = 4.1 \text{ ns (typ.)}$  at  $V_{CC} = 5 \text{ V}$
- Low power dissipation:  $I_{CC} = 2 \mu A \text{ (max)}$  at  $T_a = 25 \text{°C}$
- High noise immunity: V<sub>NIH</sub> = V<sub>NIL</sub> = 28% V<sub>CC</sub> (min)
- 5.5-V Tolerant inputs.
- Balanced propagation delays:  $t_{pLH} \simeq t_{pHL}$
- Wide operating voltage range:  $V_{CC}$  (opr) = 2~5.5 V
- Low Noise:  $V_{OLP} = 0.8 \text{ V (max.)}$

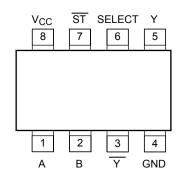


Weight SSOP8-P-0.65: 0.02 g (typ.) SSOP8-P-0.50A: 0.01 g (typ.)

### Marking



## Pin Assignment (top view)



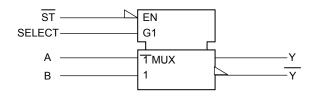
# Absolute Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	nbol Rating		
Supply voltage range	V <sub>CC</sub>	-0.5~7.0	V	
DC input voltage	V <sub>IN</sub>	-0.5~7.0	V	
DC output voltage	V <sub>OUT</sub>	-0.5~V <sub>CC</sub> + 0.5	V	
Input diode current	I <sub>IK</sub>	-20	mA	
Output diode current	lok	±20	mA	
DC output current	lout	±25	mA	
DC V <sub>CC</sub> /ground current	I <sub>CC</sub>	±50	mA	
Dower discipation	D-	300 (SM8)	mW	
Power dissipation	P <sub>D</sub>	200 (US8)	11100	
Storage temperature	T <sub>stg</sub>	-65~150	°C	
Lead temperature (10 s)	TL	260	°C	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

## **Logic Diagram**



#### **Truth Table**

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INPUTS				OUTPUTS			
ST	SELECT	Α	В	Y	Y		
Н	Х	Х	Х	L	Н		
L	L	┙	X	L	H		
L	L	Н	Х	Н	Ш		
L	Н	X	L	L	Н		
L	Н	Х	Н	Н	L		

X : Don't Care

## **Operating Ranges**

Characteristics	Symbol	Rating	Unit
Supply voltage	V <sub>CC</sub>	2.0~5.5	V
Input voltage	V <sub>IN</sub>	0~5.5	V
Output voltage	V <sub>OUT</sub>	0~V <sub>CC</sub>	V
Operating temperature	T <sub>opr</sub>	-40~85	°C
Input rice and fall time	dt/dv	0~100 (V <sub>CC</sub> = 3.3 ± 0.3 V)	ns/V
Input rise and fall time	dildv	0~20 (V <sub>CC</sub> = 5 ± 0.5 V)	115/V

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# **Electrical Characteristics**

## **DC Characteristics**

				٦	「a = 25°0		Ta = -4	0~85°C		
Characteristics	Symbol	Test Condition		V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	Unit
				2.0	1.50	_	_	1.50	_	
High-level input voltage	V <sub>IH</sub>	_		3.0~ 5.5	V <sub>CC</sub> × 0.7	_	_	V <sub>CC</sub> × 0.7	_	V
				2.0	_	_	0.50	_	0.50	V
Low-level input voltage	V <sub>IL</sub>	_		3.0~ 5.5	_		V <sub>CC</sub> × 0.3	_	V <sub>CC</sub> × 0.3	
	Vон	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -50 μA	2.0	1.9	2.0	_	1.9	_	V
				3.0	2.9	3.0	_	2.9	_	
High-level output voltage				4.5	4.4	4.5	_	4.4	_	
			I <sub>OH</sub> = -4 mA	3.0	2.58	_	_	2.48	_	
			I <sub>OH</sub> = -8 mA	4.5	3.94	_	_	3.80	_	
		V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 50 μA	2.0	_	0.0	0.1	_	0.1	V
				3.0	_	0.0	0.1	_	0.1	
Low-level output voltage	$V_{OL}$			4.5	_	0.0	0.1	_	0.1	
			I <sub>OL</sub> = 4 mA	3.0	_	_	0.36	_	0.44	
			I <sub>OL</sub> = 8 mA	4.5	_	_	0.36	_	0.44	
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = 5.5 V or GND		0~ 5.5		_	±0.1	_	±1.0	μА
Quiescent supply current	Icc	V <sub>IN</sub> = V <sub>CC</sub> or GND		5.5		_	2.0	_	20.0	μΑ

# AC Characteristics (Input: $t_r = t_f = 3$ ns)

Characteristics	Symbol Test Condition				Ta = 25°C			Ta = -40~85°C		Unit
Cital acteristics	Symbol	rest Condition	V <sub>CC</sub> (V)	C <sub>L</sub> (pF)	Min.	Тур.	Max.	Min.	Max.	Unit
			3.3 ± 0.3	15	_	6.2	9.7	1.0	11.5	
Propagation Delay Time	t <sub>pLH</sub>		3.3 ± 0.3	50	_	8.7	13.2	1.0	15.0	ns
(A, B – Y)	t <sub>pHL</sub>		5.0 ± 0.5	15	_	4.1	6.4	1.0	7.5	
			3.0 ± 0.5	50	_	5.6	8.4	1.0	9.5	
			3.3 ± 0.3	15	_	8.4	13.2	1.0	15.5	- ns
Propagation Delay Time	<sup>t</sup> pLH <sup>t</sup> pHL			50	_	10.9	16.7	1.0	19.0	
(SELECT – Y)			5.0 ± 0.5	15	_	5.3	8.1	1.0	9.5	
		0.0 ± 0.3	50	_	6.8	10.1	1.0	11.5		
			3.3 ± 0.3	15	_	8.7	13.6	1.0	16.0	
Propagation Delay Time	t <sub>pLH</sub>	t <sub>pLH</sub> t <sub>pHL</sub>	3.5 ± 0.5	50	_	11.2	17.1	1.0	19.5	ns
( <del>ST</del> – Y)	t <sub>pHL</sub>		5.0 + 0.5	15	_	5.6	8.6	1.0	10.0	115
		3.0 ± 0.5	50	_	7.1	10.6	1.0	12.0		
Input Capacitance	C <sub>IN</sub>				_	4	10	_	10	pF
Power Dissipation Capacitance	C <sub>PD</sub>	(Note 1)			_	20	_	_		pF

Note 1: $C_{PD}$  is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

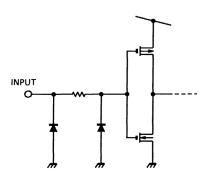
Average operating current can be obtained by the equation :

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$ 

Noise Characteristics (Ta = 25°C, input:  $t_r = t_f = 3$  ns)

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Тур.	Limit	Unit
Quiet output maximum dynamic V <sub>OL</sub>	V <sub>OLP</sub>	C <sub>L</sub> = 50 pF	5.0	0.3	0.8	V
Quiet output minimum dynamic V <sub>OL</sub>	V <sub>OLV</sub>	C <sub>L</sub> = 50 pF	5.0	-0.3	-0.8	V
Minimum high level dynamic input voltage	V <sub>IHD</sub>	C <sub>L</sub> = 50 pF	5.0	_	3.5	٧
Maximum low level dynamic input voltage	V <sub>ILD</sub>	C <sub>L</sub> = 50 pF	5.0		1.5	٧

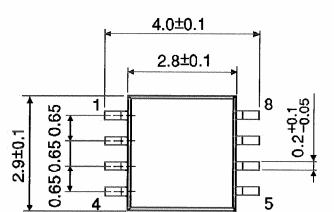
# **Input Equivalent Circuit**

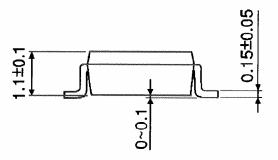


Unit: mm

# **Package Dimensions**

SSOP8-P-0.65



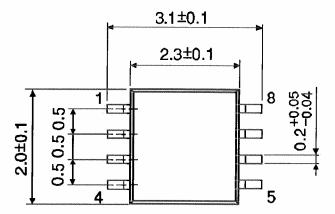


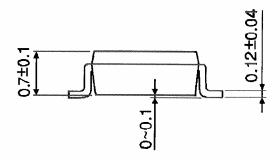
5

Weight: 0.02 g (typ.)

# **Package Dimensions**

SSOP8-P-0.50A Unit: mm





6

Weight: 0.01 g (typ.)

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20070701-EN GENERAL

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